

Commercial Announcements

New Philips XRD Software

The latest version of Philips Analytical's APD1700 X-ray diffraction software for DEC VAX and PDP computers incorporates an increased range of analytical modules and features to improve measurement performance and aid data interpretation.

This is the first XRD package to offer an outstanding operating convenience of a user interface based on windowing for the DEC VMS operating system.

In addition to automatic phase identification and quantitative determination, APD1700 now includes enhanced facilities for residual stress, texture, line profile (crystallite size/microstrain) and crystallographic analysis.

Two New Modules

Pattern treatment is based on a unique multipass search procedure – which ensures rapid, reliable detection of both sharp and broad peaks. A new profile fitting module to find hidden peaks and resolve overlapping lines adds further to the already powerful qualitative analysis capability.

Also newly introduced is an expanded graphics display module, including options for visual monitoring of intermediate data and three-dimensional presentation for easy comparison of multiple scans.

Efficient Operation

The complete JCPDS Powder Diffraction File may be supplied on magnetic disc or as the Philips Total Access Diffraction Database on CD-ROM. Pattern matching is speeded by the ability to create user-specific sub-files.

Running under the multi-user, multi-tasking VMS and RSX operating systems, APD1700 permits economical centralised control of multiple diffractometers – while operators can work simultaneously on program set-up, measurement and examination of results. Flexible software design enables users' own databases and special routines to be introduced, allowing easy adaptation to meet the most demanding research and routine needs.

For further information:

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New D 5000 X-ray Diffractometer from Siemens

Siemens has just introduced a new X-ray powder diffractometer designed to provide improved performance and greater flexibility for polycrystalline diffraction.

Featuring a new, high resolution goniometer, the D 5000 X-ray Diffractometer operates in horizontal or vertical mode and can be converted quickly from Theta-Theta to Theta-2 Theta geometry. The system includes a 3.0 kW X-ray generator, a radiation safety enclosure and counting electronics. It can also be operated with a Siemens 18.0 kW rotating anode X-ray generator. To optimize the system for specific applications, it can be configured with:

- PC or MicroVAX host computer.
- Computer-controlled slit system for resolution selection and divergence control.
- Multi-position sample changer.
- Combined stress/texture attachment for psi or omega stress analysis and texture studies on the same sample.
- Solid-state or position sensitive detectors.
- Programmable rotating sample holder for scans or selected azimuthal positions.

The system includes complete support of JCPDS databases for phase characterization of polycrystalline samples. Other software available for the D 5000 supports 3-D texture plotting and calculation of orientation distribution functions, stress analysis, temperature studies and aluminum bath ratio analysis.

For more information in USA or Canada:
Siemens Analytical X-Ray Instruments, Inc.
6300 Enterprise Lane
Madison, WI 53719
TEL: (608) 276-3000
FAX: (608) 276-3015

For more information worldwide:
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Supplier Source Directory

X-Ray Diffraction Analysis Service

- Inorganic materials our specialty: refractories, abrasives, minerals, ceramics
- Qualitative and quantitative analysis
- Powder camera technique for very small specimens
- Average crystallite size
- Optical microscopy, including identification of mineral forms, contaminants, etc. in various materials
- Identification of asbestos
- Other services include X-ray fluorescence, emission spectroscopy, wet chemical and sieve analysis

Washington Mills Electro Minerals Corporation
P. O. Box 423 • Niagara Falls, NY 14302
(716) 278-6796, - 6728

Advertising Announcements

Supplier Source Directory

Examples of suggested styles for listings in the Supplier Source Directory.

John R. Doe
Professor of Chemistry and Geology
The Eastern University
Department of Chemistry
N.Y.C., N.Y.
Telephone
FAX

Consulting Services in XRD: Mineralogy

High Resolution Results

Write to: XYZ Co.
Stuttgart, W. Germany

Sample holder designed for samples of large particles ($\geq 80\mu\text{m}$).

XYZ Co.
East Diagram
Bombay, India

High Temperature

Tc(K)	Compound
551	$\text{Ba}_{0.8}\text{Sr}_{1.2}\text{NaNb}_5\text{O}_{15}$
—	$\text{BaSrKNb}_5\text{O}_{15}$
547	$\text{BaSrNa}_{0.5}\text{K}_{0.5}\text{Nb}_5\text{O}_{15}$
150	$\text{BaSrNaNb}_5\text{O}_{15}$
225	$\text{Ba}_2\text{LiTa}_5\text{O}_{15}$
428	$\text{Ba}_2\text{NaNb}_{1.25}\text{Ta}_{3.75}\text{O}_{15}$

Write to:
XYZ Company
West Blank, PA
Telephone

Powder Diffraction announces the Supplier Source Directory – designed for use by those who wish to make known their special services to the X-ray diffraction community. Rates are modest (no discounts for agencies), beginning at \$125.00 for one insertion (business card size).

For details please write or call Mary M. Rossi, Advertising Manager, JCPDS-ICDD at Swarthmore. (215-328-9403).

Used Analytical X-ray Systems & Accessories Being Offered

Write to Receive Information
Name/Title _____
Institution/Company _____
Address _____
City _____ State _____
Country _____ Mail Code _____

XRD Company
Roentgen, Pennsylvania
Telephone

X-ray Diffraction Software Personal Computers

XYZ Software Inc.
Cheshire, U.K.
Tel.
FAX

announces the availability of the following software:

System 1:	Forensics	
System 2:	CD-ROM	PC

Examples of possible insertions are indicated on the Directory shown here (80% of actual size.)